TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74VCX02FT,TC74VCX02FK

Low-Voltage Quad 2-Input NOR Gate with 3.6-V Tolerant Inputs and Outputs

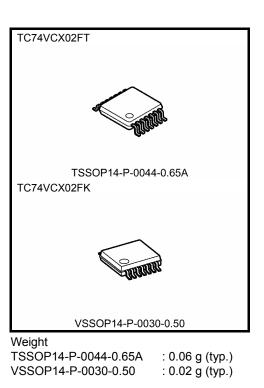
The TC74VCX02FT/FK is a high-performance CMOS 2-input NOR gate which is guaranteed to operate from 1.2-V to 3.6-V. Designed for use in 1.5V, 1.8V, 2.5V or 3.3V systems, it achieves high-speed operation while maintaining the CMOS low power dissipation.

It is also designed with overvoltage tolerant inputs and outputs up to 3.6 V.

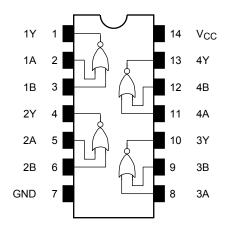
All inputs are equipped with protection circuits against static discharge.

Features

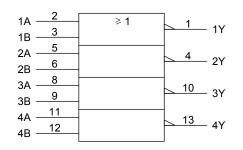
- Low-voltage operation: VCC = 1.2~3.6 V
- High-speed operation: $t_{pd} = 2.8 \text{ ns} (\text{max}) (V_{CC} = 3.0 \sim 3.6 \text{ V})$
 - $t_{pd} = 3.7 \text{ ns} (\text{max}) (\text{V}_{CC} = 2.3 \sim 2.7 \text{ V})$
 - : $t_{pd} = 7.4 \text{ ns} (\text{max}) (V_{CC} = 1.65 \sim 1.95 \text{ V})$
 - : $t_{pd} = 14.8 \text{ ns} (\text{max}) (V_{CC} = 1.4 \sim 1.6 \text{ V})$
 - $t_{pd} = 37.0 \text{ ns} (\text{max}) (\text{V}_{CC} = 1.2 \text{ V})$
- Output current: $I_{OH}/I_{OL} = \pm 24 \text{ mA (min)} (V_{CC} = 3.0 \text{ V})$
 - $: I_{OH}/I_{OL} = \pm 18 \text{ mA} (min) (V_{CC} = 2.3 \text{ V})$
 - $: I_{OH/IOL} = \pm 6 \text{ mA (min) (V}_{CC} = 1.65 \text{ V)}$ $: I_{OH/IOL} = \pm 2 \text{ mA (min) (V}_{CC} = 1.4 \text{ V)}$
- Latch-up performance: -300 mA
- ESD performance: Machine model $\geq \pm 200 \text{ V}$
 - Human body model $\geq \pm 2000 \text{ V}$
- Package: TSSOP and VSSOP (US)
- Power-down protection provided on all inputs and outputs



Pin Assignment (top view)



IEC Logic Symbol



Truth Table

Inp	uts	Outputs
А	В	Y
L	L	Н
L	Н	L
Н	L	L
Н	Н	L

Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit	
Power supply voltage	V _{CC}	-0.5~4.6	V	
DC input voltage	V _{IN}	-0.5~4.6	V	
DC output voltage	Vour	-0.5~4.6 (Note 2)	V	
DC output voltage	Vout	-0.5~V _{CC} + 0.5(Note 3)	v	
Input diode current	I _{IK}	-50	mA	
Output diode current	IOK	±50 (Note 4)	mA	
DC output current	IOUT	±50	mA	
Power dissipation	PD	180	mW	
DC V _{CC} /ground current	I _{CC} /I _{GND}	±100	mA	
Storage temperature	T _{stg}	-65~150	°C	

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

- Note 2: $V_{CC} = 0 V$
- Note 3: High or low state. IOUT absolute maximum rating must be observed.
- Note 4: $V_{OUT} < GND, V_{OUT} > V_{CC}$

Operating Ranges (Note 1)

Characteristics	Symbol	Rating	Unit	
Power supply voltage	V _{CC}	1.2~3.6	V	
Input voltage	V _{IN}	-0.3~3.6	V	
Output voltage	Vout	0~3.6 (Note 2)	V	
Output voltage	VOUT	0~V _{CC} (Note 3)	-	
		±24 (Note 4)		
Output current	IOH/IOL	±18 (Note 5)	mA	
Output current	'OH/'OL	±6 (Note 6)	ША	
		±2 (Note 7)		
Operating temperature	T _{opr}	-40~85	°C	
Input rise and fall time	dt/dv	0~10 (Note 8)	ns/V	

Note 1: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

Note 2: $V_{CC} = 0 V$

Note 3: High or low state

Note 4:	$V_{CC}=3.0\text{~}3.6~V$
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- Note 5: $V_{CC} = 2.3 \sim 2.7 \text{ V}$
- Note 6: $V_{CC} = 1.65 \sim 1.95 V$
- Note 7: $V_{CC} = 1.4 \sim 1.6 V$
- Note 8: $V_{IN} = 0.8 \sim 2.0 \text{ V}, V_{CC} = 3.0 \text{ V}$

Electrical Characteristics

DC Characteristics (Ta = -40 to 85° C, 2.7 V < V_{CC} \leq 3.6 V)

Characteristi	<u></u>	Symbol	Tost C	condition		Min	Мах	Unit
Characteristi	65	Symbol	Test C			IVIIII	IVIAX	Unit
Input voltage	H-level	VIH	—		2.7~3.6	2.0	_	V
input voltage	L-level	VIL			2.7~3.6	_	0.8	v
P Output voltage	H-level V _{OH}			I _{OH} = -100 μA	2.7~3.6	V _{CC} - 0.2	—	
		V _{OH}	$V_{IN} = V_{IL}$	I _{OH} = -12 mA	2.7	2.2	_	
		_		I _{OH} = -18 mA	3.0	2.4	_	v
				I _{OH} = -24 mA	3.0	2.2	_	
	L-level Voi	VIN = VIH or VIL	I _{OL} = 100 μA	2.7~3.6	_	0.2		
			I _{OL} = 12 mA	2.7	_	0.4		
	L-IEVEI	V _{OL}	$\Lambda IN = \Lambda IH \text{ OL} \Lambda I\Gamma$	I _{OL} = 18 mA	3.0	_	0.4	
				I _{OL} = 24 mA	3.0	_	0.55	
Input leakage current		I _{IN}	$V_{IN} = 0$ to 3.6 V		2.7~3.6	_	±5.0	μA
Power-off leakage curre	ent	IOFF	V_{IN} , $V_{OUT} = 0$ to 3.6 V	/	0	_	10.0	μA
Quiescent supply curre	Quiescent supply current		$V_{IN} = V_{CC}$ or GND		2.7~3.6	_	20.0	
Increase in I _{CC} per inp	Increase in Las ner input	Icc	$V_{CC} \leq V_{IN} \leq 3.6 \text{ V}$		2.7~3.6		±20.0	μA
increase in ICC per inp	ui	∆l _{CC}	$V_{IH} = V_{CC} - 0.6 \ V$		2.7~3.6	_	750	

DC Characteristics (Ta = -40 to 85°C, 2.3 V \leq V_{CC} \leq 2.7 V)

Characterist	ice	Symbol	Test	Condition		Min	Max	Unit
Characterist	103	Symbol	1630			IVIIII	IVIAA	Onit
Input voltage	H-level	VIH		—	2.3~2.7	1.6	_	v
L-level		VIL		_	2.3~2.7	_	0.7	v
H-lev				I _{OH} = -100 μA	2.3~2.7	V _{CC} - 0. 2		
	H-level	VOH	$V_{IN} = V_{IL}$	$I_{OH} = -6 \text{ mA}$	2.3	2.0	_	
				$I_{OH} = -12 \text{ mA}$	2.3	1.8	_	V
Output voltage				I _{OH} = -18 mA	2.3	1.7	_	
			$V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 100 \ \mu A$	2.3~2.7	_	0.2	
	L-level	V _{OL}		$I_{OL} = 12 \text{ mA}$	2.3	_	0.4	
				$I_{OL} = 18 \text{ mA}$	2.3	_	0.6	
Input leakage current		I _{IN}	$V_{IN} = 0$ to 3.6 V		2.3~2.7	_	±5.0	μA
Power-off leakage current		IOFF	V_{IN} , $V_{OUT} = 0$ to 3.6	V _{IN} , V _{OUT} = 0 to 3.6 V		_	10.0	μA
Quies and a second second			$V_{IN} = V_{CC}$ or GND		2.3~2.7	_	20.0	•
Quiescent supply curre	5111	Icc	$V_{CC} \stackrel{\scriptstyle \leq}{=} V_{IN} \stackrel{\scriptstyle \leq}{=} 3.6 \ V$		2.3~2.7		±20.0	μA

DC Characteristics (Ta = –40 to 85°C, 1.65 V \leq V_{CC} < 2.3 V)

Characteristi	Characteristics		Test Condition		V _{CC} (V)	Min	Max	Unit
H-level		VIH	-	_		0.65 × V _{CC}		
Input voltage	L-level	VIL			1.65~2.3	_	$0.2 \times V_{CC}$	V
	H-level V _{OH}	V _{OH} V _{IN} = V _{IL}	I _{OH} = -100 μA	1.65~2.3	V _{CC} - 0.2	_		
Output voltage		-		I _{OH} = -6 mA	1.65	1.25		V
	L-level	Mai		I _{OL} = 100 μA	1.65~2.3	_	0.2	
	L-level	V _{OL}	$V_{IN} = V_{IH} \text{ or } V_{IL}$	I _{OL} = 6 mA	1.65		0.3	
Input leakage current		I _{IN}	V _{IN} = 0 to 3.6 V	-	1.65~2.3	_	±5.0	μA
Power-off leakage curr	Power-off leakage current		V _{IN} , V _{OUT} = 0 to 3.6 V	,	0	_	10.0	μA
Online and an and a summat			$V_{IN} = V_{CC}$ or GND		1.65~2.3		20.0	
Quiescent supply curre	:11	Icc	$V_{CC} \leq V_{IN} \leq 3.6 \text{ V}$		1.65~2.3		±20.0	μA

DC Characteristics (Ta = –40 to 85°C, 1.4 V \leq V_{CC} < 1.65 V)

Characteristics		Symbol	Test Condition		V _{CC} (V)	Min	Max	Unit
H-level		VIH		—		$0.65 \times V_{CC}$	_	V
	L-level	VIL	_		1.4~1.65		$\begin{array}{c} 0.05 \times \\ V_{CC} \end{array}$	v
Output voltage	H-level	el V _{OH}	V _{OH} V _{IN} = V _{IL}	I _{OH} = -100 μA	1.4~1.65	V _{CC} - 0.2		- V
				$I_{OH} = -2 \text{ mA}$	1.4	1.05		
Oulput Voltage	L-level	vel V _{OL}	VIN = VIH or VII	I _{OL} = 100 μA	1.4~1.65		0.05	
				$I_{OL} = 2 \text{ mA}$	1.4		0.35	
Input leakage current		I _{IN}	$V_{IN} = 0$ to 3.6 V		1.4~1.65		±5.0	μA
Power-off leakage curre	Power-off leakage current		V_{IN} , $V_{OUT} = 0$ to 3.6 V	V	0		10.0	μA
Quiescent supply current			$V_{IN} = V_{CC}$ or GND		1.4~1.65		20.0	
Quiescent supply curre	110	Icc	$V_{CC} \leq V_{IN} \leq 3.6 \text{ V}$		1.4~1.65	—	±20.0	μA

DC Characteristics (Ta = -40 to 85°C, 1.2 V \leq V_{CC} < 1.4 V)

Characteristics		Symbol	Test Condition			Min	Max	Unit
					V _{CC} (V)			
Input voltage		VIH	—		1.2~1.4	$0.8 \times V_{CC}$	—	v
		VIL	—		1.2~1.4		$\begin{array}{c} 0.05 \times \\ V_{CC} \end{array}$	v
Output voltage	H-level	V _{OH}	$V_{IN} = V_{IL}$	I _{OH} = -100 μA	1.2	V _{CC} - 0.1	_	V
	L-level	V _{OL}	$V_{IN} = V_{IH} \text{ or } V_{IL}$	I _{OL} = 100 μA	1.2		0.05	
Input leakage current		I _{IN}	$V_{IN} = 0$ to 3.6 V		1.2		±5.0	μA
Power-off leakage curre	Power-off leakage current I _{OFF} V _{IN} , V _{OUT} = 0 to 3.6 V			0	—	10.0	μA	
Quieseent aunaly aurrent		Icc	$V_{IN} = V_{CC} \text{ or } GND$		1.2		20.0	
Quiescent supply curre	Quiescent supply current		$V_{CC} \leq V_{IN} \leq 3.6 \text{ V}$		1.2		±20.0	μA

AC Characteristics (Ta = -40 to 85°C, input: $t_r = t_f = 2.0$ ns) (Note 1)

Characteristics	Symbol	Test C		Min	Max	Unit	
onaraotenotios	Cymbol		onation	V _{CC} (V)	IVIIII	Max	Onit
Propagation delay time			CL = 15 pF, RL = 2 kΩ	1.2	3.0	37.0	
	+		$O_{L} = 10 \text{ pr}, \text{ N}_{L} = 2 \text{ M}_{2}$	$\textbf{1.5}\pm\textbf{0.1}$	2.0	14.8	
	t _{pLH} t _{pHL}	Figure 1, Figure 2		$\textbf{1.8} \pm \textbf{0.15}$	1.5	7.4	ns
	φnc		$C_L = 30 \text{ pF}, \text{ R}_L = 500 \Omega$	$\textbf{2.5}\pm\textbf{0.2}$	0.8	3.7	
				$\textbf{3.3}\pm\textbf{0.3}$	0.6	2.8	
			CL = 15 pF, RL = 2 kΩ	1.2		1.5	
	+			1.5 ± 0.1		1.5	
Output to output skew	t _{osLH}	(Note 2)		1.8 ± 0.15		0.5	ns
	t _{osHL}		$C_L = 30 \text{ pF}, \text{ R}_L = 500 \Omega$	2.5 ± 0.2		0.5	
				$\textbf{3.3}\pm\textbf{0.3}$		0.5	

Note 1: For $C_L = 50$ pF, add approximately 300 ps to the AC maximum specification.

Note 2: Parameter guaranteed by design. $(t_{osLH} = |t_{pLHm} - t_{pLHn}|, \ t_{osHL} = |t_{pHLm} - t_{pHLn}|)$

Dynamic Switching Characteristics (Ta = 25°C, input: $t_r = t_f = 2.0 \text{ ns}$, $C_L = 30 \text{ pF}$)

Characteristics	Symbol	Test Condition		V _{CC} (V)	Тур.	Unit
		$V_{IH} = 1.8 \text{ V}, V_{IL} = 0 \text{ V}$ (Note)	1.8	0.25	
Quiet output maximum dynamic V _{OL}	V _{OLP}	$V_{IH} = 2.5 \text{ V}, V_{IL} = 0 \text{ V}$ (Note)	2.5	0.6	V
02		$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$ (Note)	3.3	0.8	
	V _{OLV}	$V_{IH} = 1.8 \text{ V}, V_{IL} = 0 \text{ V}$ (Note)	1.8	-0.25	v
Quiet output minimum dynamic V _{OL}		$V_{IH} = 2.5 \text{ V}, V_{IL} = 0 \text{ V}$ (Note)	2.5	-0.6	
02		$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$ (Note)	3.3	-0.8	
		$V_{IH} = 1.8 \text{ V}, V_{IL} = 0 \text{ V}$ (Note)	1.8	1.5	
Quiet output minimum dynamic V _{OH}	V _{OHV}	$V_{IH} = 2.5 \text{ V}, V_{IL} = 0 \text{ V}$ (Note)	2.5	1.9	V
		$V_{IH} = 3.3 V, V_{IL} = 0 V$ (Note)	3.3	2.2	

Note: Parameter guaranteed by design.

Capacitive Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Тур.	Unit
Input capacitance	C _{IN}	_	1.8, 2.5, 3.3	6	pF
Power dissipation capacitance	C _{PD}	f _{IN} = 10 MHz (Note) 1.8, 2.5, 3.3	20	pF

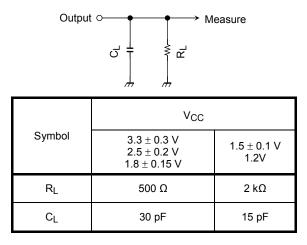
Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/4$ (per gate)

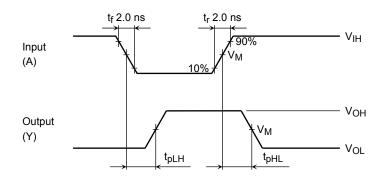
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AC Test Circuit





AC Waveform



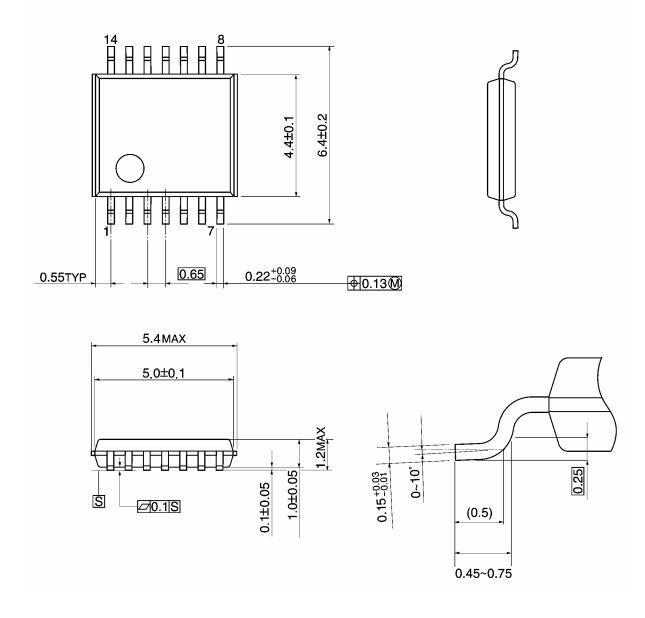
Symbol	V _{CC}				
	$3.3\pm0.3~V$	$2.5\pm0.2\;V$	$1.8\pm0.15\;V$	$1.5\pm0.1~\text{V}$	1.2 V
VIH	2.7 V	V _{CC}	V _{CC}	V _{CC}	V _{CC}
VM	1.5 V	V _{CC} /2	V _{CC} /2	V _{CC} /2	V _{CC} /2

Figure 2 t_{pLH}, t_{pHL}

Package Dimensions

TSSOP14-P-0044-0.65A

Unit: mm



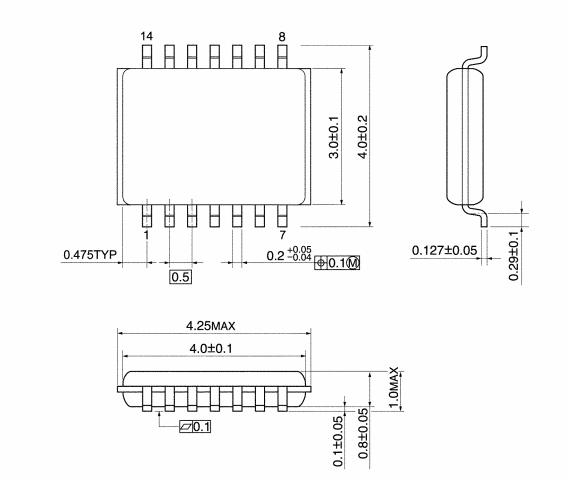
Weight: 0.06 g (typ.)



Package Dimensions

VSSOP14-P-0030-0.50

Unit: mm



Weight: 0.02 g (typ.)

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20070701-EN GENERAL

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